

DESCRIPTION

The XPX409FD is P channel enhancement mode power effect transistor which is produced using high cell density advanced trench technology.

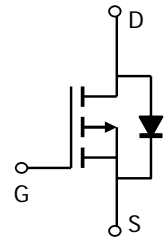
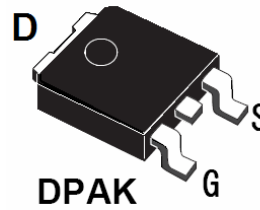
The high density process is especially able to minimize on-state resistance. These devices are especially suited for low voltage application power management DC-DC converters.

APPLICATIONS

- ◆ Power Management
- ◆ DC/DC Converter
- ◆ Load Switch

FEATURE

- ◆ -60V/-50A, $R_{DS(ON)}=30\text{ m}\Omega(\text{typ.})@V_{GS}=-10\text{V}$
- ◆ -60V/-30A, $R_{DS(ON)}=40\text{ m}\Omega(\text{typ.})@V_{GS}=-4.5\text{V}$



Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
XPX409FD	XPX409FD	TO-252	-	-	-

■ PART NUMBER INFORMATION

XPX409AA-BB C	A= Package Code T: TO-252 BB=Handing Code TR: Tape&Reel C=Lead Plating Code G: Green Product P: Pb free
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■ ORDERING INFORMATION

Part Number	Package Code	Package	Shipping
XPX409AT-TRG	T	TO-252	2500EA / T&R

- ※ Year Code : 0~9
- ※ Week Code : A~Z(1-26); a~z(27~52)
- ※ G : Green Product. This product is RoHS compliant.

■ ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless otherwise noted)

Parameter	Symbol	Maximum	Units		
Drain-Source Voltage	V_{DS}	-60	V		
Gate-Source Voltage	V_{GS}	± 20	V		
Continuous Drain Current ^G	I_D	$T_C=25^\circ\text{C}$	-50		
		$T_C=100^\circ\text{C}$	-18		
Pulsed Drain Current ^C	I_{DM}	-60	A		
Avalanche Current ^C	I_{AR}	-50	A		
Repetitive avalanche energy $L=0.1\text{mH}$ ^C	E_{AR}	33.8	mJ		
Power Dissipation ^B	P_D	$T_C=25^\circ\text{C}$	60		
		$T_C=100^\circ\text{C}$	30		
Power Dissipation ^A	P_{DSM}	$T_A=25^\circ\text{C}$	2.5		
		$T_A=70^\circ\text{C}$	1.6		
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175	$^\circ\text{C}$		
Thermal Characteristics					
Parameter	Symbol	Typ	Max	Units	
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	$t \leq 10\text{s}$	16.7	25	$^\circ\text{C/W}$
Maximum Junction-to-Ambient ^A		Steady-State	40	50	$^\circ\text{C/W}$
Maximum Junction-to-Case ^C	$R_{\theta JC}$	Steady-State	1.9	2.5	$^\circ\text{C/W}$

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress rating only and functional device operation is not implied

■ **ELECTRICAL CHARACTERISTICS** ($T_A=25^\circ\text{C}$ Unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
Static Parameters						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D = -250\mu A$	-60			V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D = -250\mu A$	-1.0		-2.5	V
I_{GSS}	Gate Leakage Current	$V_{DS}=0V, V_{GS}=\pm 25V$			± 100	nA
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-48V, V_{GS}=0$			-1	uA
		$V_{DS}=-48V, V_{GS}=0$ $T_J=85^\circ\text{C}$			-5	
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS}=-10V, I_D = -20 A$		30	40	m Ω
		$V_{GS} = -4.5V, I_D = -20 A$		40	55	
Source-Drain Diode						
V_{SD}	Diode Forward Voltage	$I_S = -1 A, V_{GS}=0V$		0.7	1.3	V
Dynamic Parameters						
Q_g	Total Gate Charge	$V_{DS} = -30V$ $V_{GS} = -10V$ $I_D = -20 A$		53		nC
Q_{gs}	Gate-Source Charge			12		
Q_{gd}	Gate-Drain Charge			13		
C_{iss}	Input Capacitance	$V_{DS} = -30V$ $V_{GS}=0V$ $f=1\text{MHz}$		1886		pF
C_{oss}	Output Capacitance			540		
C_{riss}	Reverse Transfer Capacitance			240		
$T_{d(on)}$	Turn-On Time	$V_{DS} = -30V$ $R_L = 1.50\Omega$ $V_{GEN} = -10V$ $R_G = 3.0\Omega$		19		nS
T_r				15		
$T_{d(off)}$	Turn-Off Time				52	
T_f				17		

Note: 1. Pulse test: pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$

2. Static parameters are based on package level with recommended wire bonding

■ **TYPICAL CHARACTERISTICS** (25°C Unless Note)

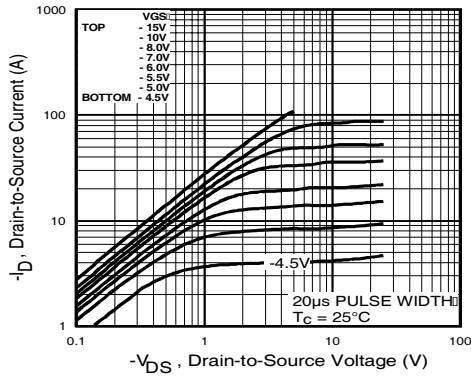


Fig 1. Typical Output Characteristics

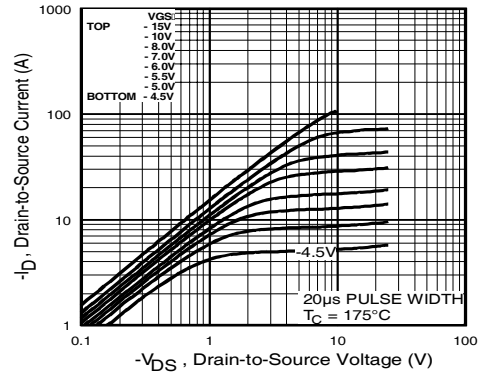


Fig 2. Typical Output Characteristics

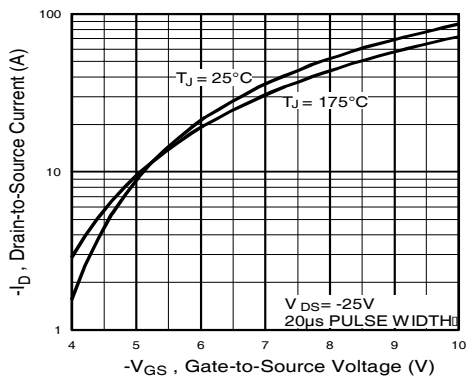


Fig 3. Typical Transfer Characteristics

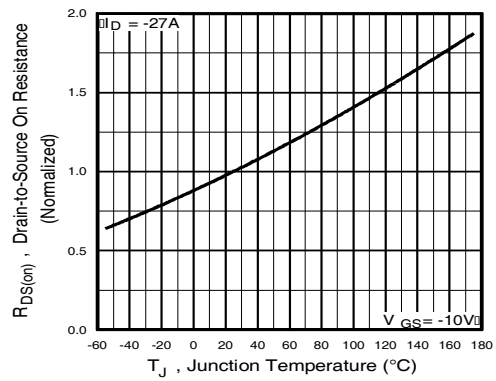


Fig 4. Normalized On-Resistance Vs. Temperature

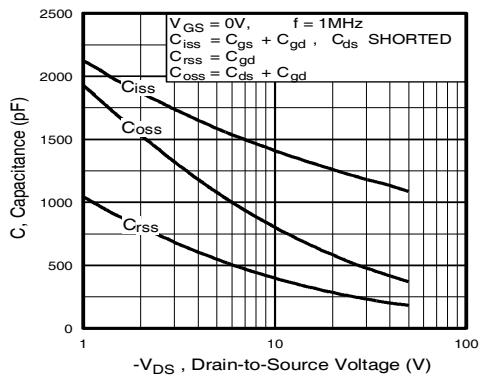


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

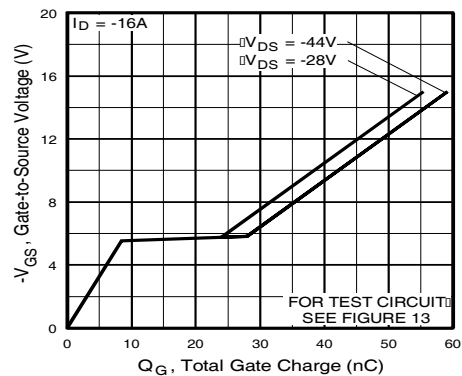


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

■ TYPICAL CHARACTERISTICS (continuous)

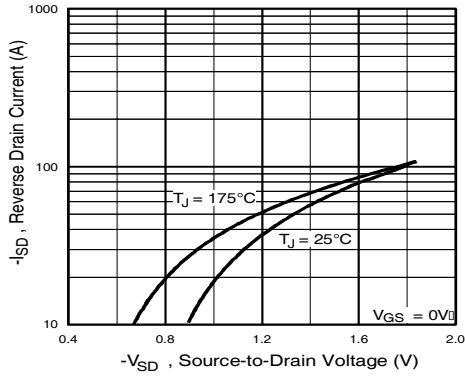


Fig 7. Typical Source-Drain Diode Forward Voltage

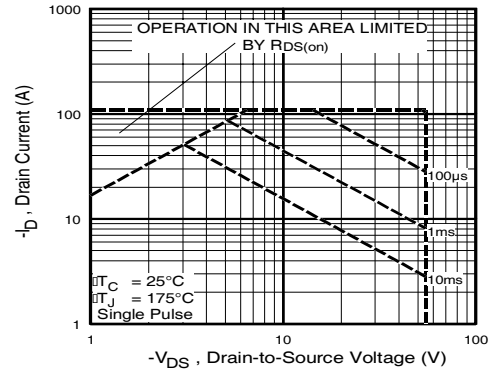


Fig 8. Maximum Safe Operating Area

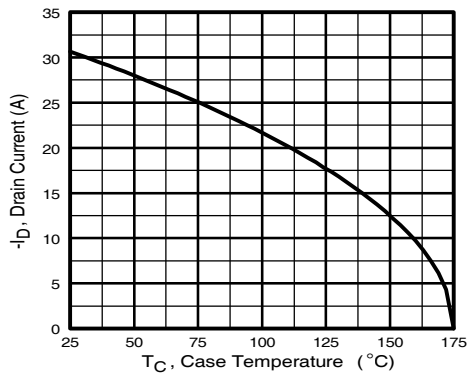


Fig 9. Maximum Drain Current Vs. Case Temperature

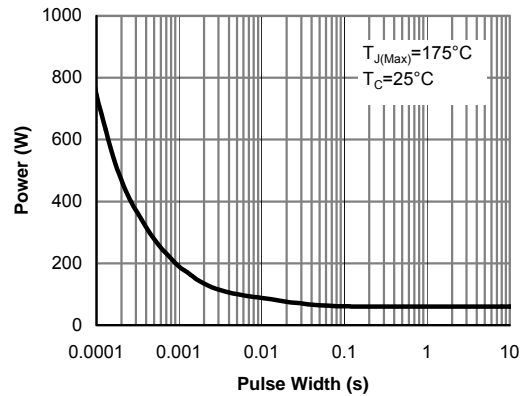
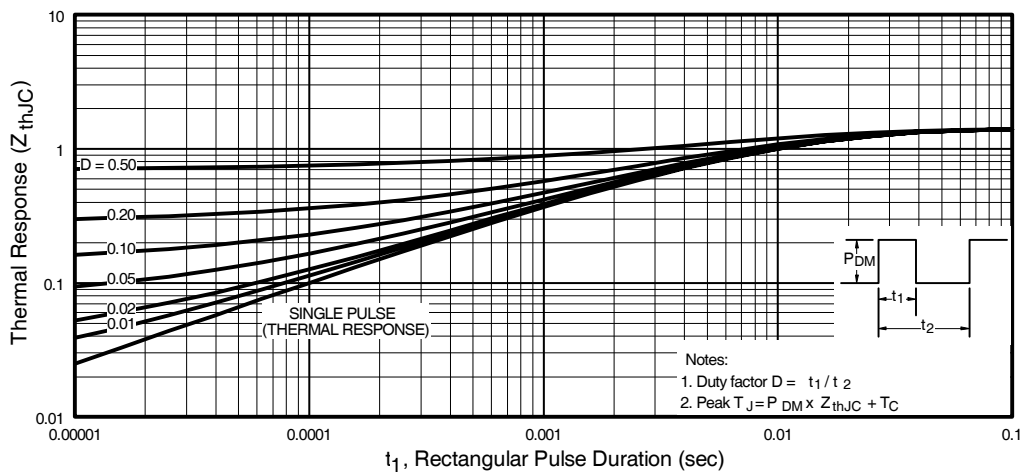
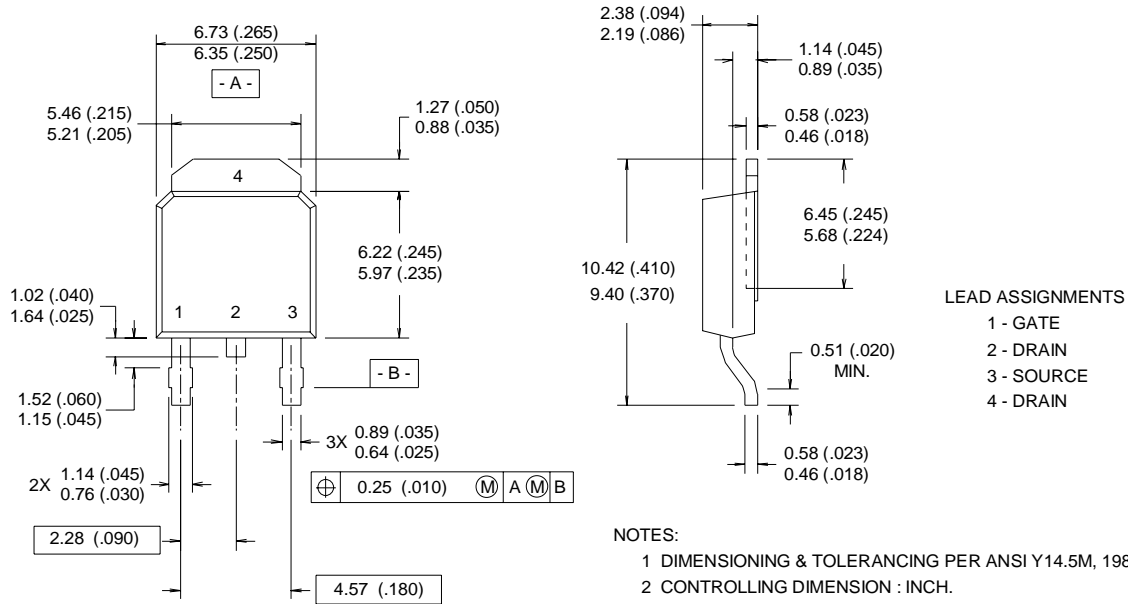


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)



TO-252 Outline Package Dimension

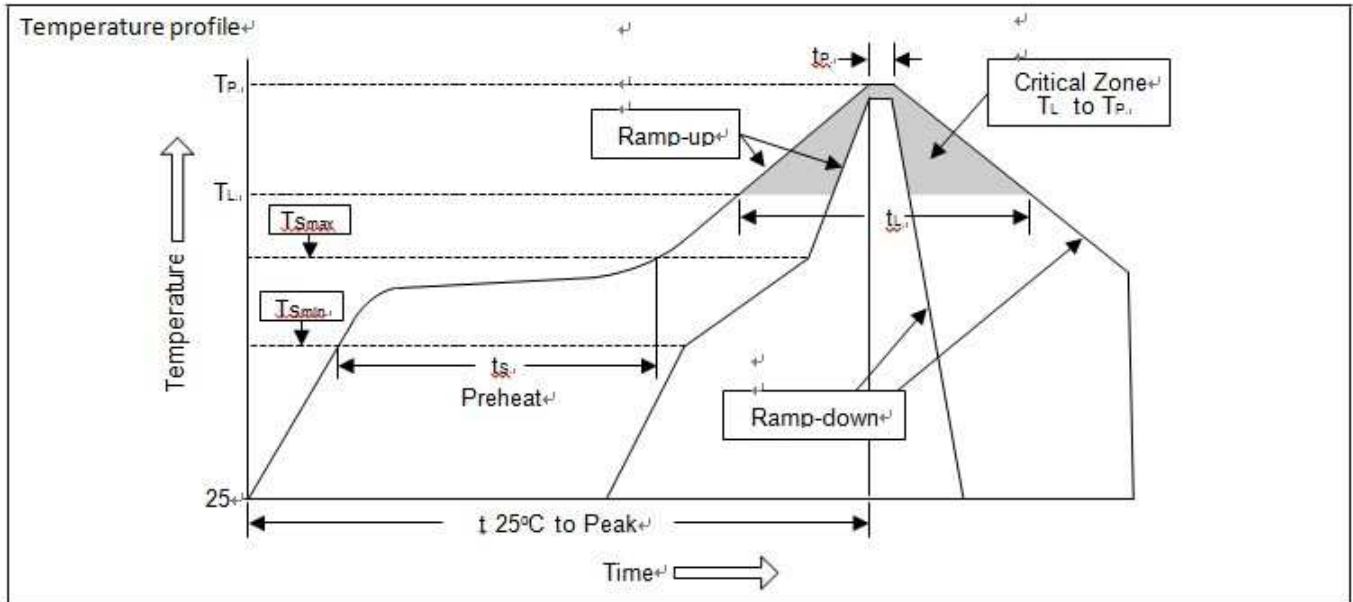
Dimensions are shown in millimeters (inches)



■ SOLDERING METHODS FOR UNIVERCHIP

Storage environment Temperature=10°C~35°C Humidity=65%±15%

Reflow soldering of surface mount device



Profile Feature	Sn-Pb Eutectic Assembly	Pb free Assembly
Average ramp-up rate (T_L to T_P)	<3°C/sec	<3°C/sec
Preheat		
-Temperature Min (T_{smin})	100°C	150°C
-Temperature Max (T_{smx})	150°C	200°C
-Time (min to max) (t_s)	60~120 sec	60~180 sec
T_{smx} to T_L		
-Ramp-up Rate	<3°C/sec	<3°C/sec
Time maintained above		
-Temperature (T_L)	183°C	217°C
-Time (t_L)	60~150 sec	60~150 sec
Peak Temperature (T_P)	240°C +0/-5°C	260°C +0/-5°C
Time within 5°C of actual Peak Temperature (t_p)	10~30 sec	20~40 sec
Ramp-down Rate	<6°C/sec	<6°C/sec
Time 25°C to Peak Temperature	<6 minutes	<6 minutes